

Chip Multilayer Ceramic Capacitors for General



A Note • Please read rating and A CAUTION (for storage, operating, rating, soldering, mounting and handling) in this catalog to prevent smoking and/or burning, etc.
 • This catalog has only typical specifications. Therefore, please approve our product specifications or transact the approval sheet for product specifications before ordering.

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Safety Standard Certified Chip Multilayer Ceramic Capacitors for General Purpose / IEC60384-14 Class X2

GA3 Series Type GB

WEB 👆

IEC60384-14 X2 Class Certified Product

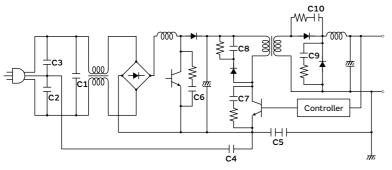
Features

1 International Standard (IEC60384-14) certified product.

Please down load Safety Standard Certification (Type GB: X2) from here. WEB

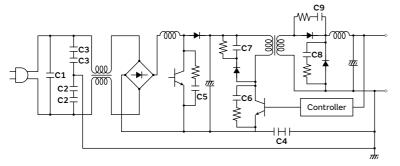
2 Can be used as a Class X2 capacitor.

Switching Power Supply - Class 1 Equipment



No.	Application	Recommend MLCC Type
C1	X Cap	Type: GB
C2		
С3	Y Cap	Type: GF
C4		
C5	Primary - Secondary Coupling	Type: GF×2

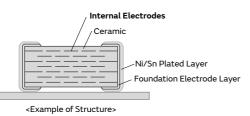
Switching Power Supply - Class 2 Equipment



No.	Application	Recommend MLCC Type	
C1	X Cap	Type: GB	
C2	Y Cap		
С3	r Cap	Type: GF×2	
C4	Primary - Secondary Coupling		

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3 Realized large capacitance value and small size while maintaining high withstand voltages by the multilayer structure.



4 Compared with conventional lead type capacitors, this product realized great reductions in size and height, with a volume of 1/10 or less, and height of 1/4 or less.

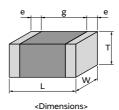
5 This product is only for reflow soldering.

Specifications

Size (mm)	5.7×5.0mm
Rated Voltage	250Vac
Capacitance	10000pF to 56000pF
Main Applications	AC-DC power supply

This catalog contains only a portion of the product lineup.

Please refer to the capacitor search tool on the Murata Web site for details.



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GA3 Series Type GB High Dielectric Constant Type 📟 Part Number List

5.7×5.0mm

T max.	Rated Voltage	TC Code	Cap.	Tol.	Part Number	P*
1.5mm	250Vac	X7R	10000pF	±10%	GA355QR7GB103KW01#	p192
			15000pF	±10%	GA355QR7GB153KW01#	p192
2.0mm	250Vac	X7R	22000pF	±10%	GA355DR7GB223KW01#	p192
2.5mm	250Vac	X7R	33000pF	±10%	GA355ER7GB333KW01#	p192
			47000pF	±10%	GA355ER7GB473KW01#	p192
2.9mm	250Vac	X7R	56000pF	±10%	GA355XR7GB563KW06#	p192

ACaution /Notice

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GA3 Series Type GB Specifications and Test Methods (1)

No	lte	em	Specification	Test Method (Ref. Standard: JIS C 5101, IEC60384)
1	Appearance		No defects or abnormalities.	Visual inspection.
2	Dimension		Within the specified dimensions.	Using calipers and micrometers.
3	Voltage Proof		No defects or abnormalities.	Measurement Point: Between the terminations Test Voltage: DC1075V Applied Time: 60±1s Charge/discharge current: 50mA max.
4	Insulation Res	sistance (I.R.)	6000MΩ or more	Measurement Point: Between the terminations Measurement Voltage: DC500±50V Charging Time: 60±5s Measurement Temperature: Room Temperature
5	Capacitance		Shown in Rated value.	Measurement Temperature: Room Temperature
6	Dissipation Fa	actor (D.F.)	0.025 max.	Measurement Frequency: 1.0±0.1kHz Measurement Voltage: AC1.0±0.2V (r.m.s.)
7	Temperature Characteristics of Capacitance		R7: Within ±15% (-55 to +125°C)	The capacitance change should be measured after 5 minutes at each specified temp. stage. Capacitance value as a reference is the value in step 3. <u>Step Temperature (°C)</u> <u>1 Reference Temp. ±2</u> <u>2 Min. Operating Temp. ±3</u> <u>3 Reference Temp. ±3</u> <u>5 Reference Temp. ±2</u> • Pretreatment Perform a heat treatment at 150+0/-10°C for 1h±5min and then let sit for 24±2h. at room condition*.
		Appearance	No defects or abnormalities.	Solder the capacitor on the test substrate A shown in
		Capacitance	Within the specified initial value.	"Complement of Test Method".
8	Vibration	D.F.	Within the specified initial value.	Kind of Vibration: A simple harmonic motion 10Hz to 55Hz to 10Hz (1min) Total amplitude: 1.5mm This motion should be applied for a period of 2h in each 3 mutually perpendicular directions (total of 6h).
9	Solderability		95% of the terminations is to be soldered evenly and continuously.	Test Method: Solder bath method Flux: Solution of rosin ethanol 25 (wt)% Preheat: 80 to 120°C for 10 to 30s Solder: Sn-3.0Ag-0.5Cu (Lead Free Solder) Solder Temp.: 245±5°C Immersion time: 2±0.5s Immersing in speed: 25±2.5mm/s.
		Appearance	No defects or abnormalities.	Test Method: Solder bath method
		Capacitance Change	Within ±10%	Solder: Sn-3.0Ag-0.5Cu (Lead Free Solder) Solder Temp.: 260±5°C Immersion time: 10±1s
	Resistance to	I.R.	1000MΩ or more	Immersing in speed: 25±2.5mm/s.
10	Soldering Heat Voltage Proof		No defects.	Exposure Time: 24±2h at room condition*. Preheat: GA355 size: 100 to 120°C for 1min and 170 to 200°C for 1min • Pretreatment Perform a heat treatment at 150+0/-10°C for 1h±5min and then let sit for 24±2h at room condition*.
11	Adhesive Strength of Termination		No removal of the terminations or other defect should occur.	Solder the capacitor on the test substrate A shown in "Complement of Test Method". 10N, 10±1s Applied Direction: In parallel with the test substrate and vertical with the capacitor side.
12	Substrate Bending Test		No defects or abnormalities.	Solder the capacitor on the test substrate B shown in "Complement of Test Method". Then apply the force in the direction shown in "Test Method of Substrate Bending Test" of "Complement of Test Method". Flexure: 1mm Holding Time: 5±1s Soldering Method: Reflow soldering

* Room Condition: Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmosphere pressure: 86 to 106kPa

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GA3 Series Type GB Specifications and Test Methods (1)

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No	lte	em	Specification	Test Method (Ref. Standard: JIS C 5101, IEC60384)
		Appearance	No defects or abnormalities.	Fix the capacitor to the supporting test substrate A (glass epoxy
		Capacitance Change	Within±15%	board) shown in "Complement of Test Method". Perform the 5 cycles according to the four heat treatments shown in the following table.
		D.F.	0.05 max.	Step Temp. (°C) Time (min)
	Temperature	I.R.	3000MΩ or more	1 Min. Operating Temp. +0/-3 30±3
13	Sudden Change	Voltage Proof	No defects.	2 Room Temp. 2 to 3 3 Max. Operating Temp. +3/-0 30±3 4 Room Temp. 2 to 3 Exposure Time: 24±2h at room condition*. • Pretreatment Perform a heat treatment at 150+0/-10°C for 1h±5min and then let sit for 24±2h at room condition*.
		Appearance	No defects or abnormalities.	Fix the capacitor to the supporting test substrate B (glass epoxy
		Capacitance Change	Within±15%	board) shown in "Complement of Test Method". Before this test, the test shown in the following is performed. • No.11 Adhesive Strength of Termination (apply force: 5N)
	High	D.F.	0.05 max.	No.12 Substrate Bending Test
14	Temperature High	I.R.	3000MΩ or more	Test Temperature: 40±2°C Test Humidity: 90 to 95%RH
	Humidity (Steady)	Voltage Proof	No defects.	Test Time: 500+24/-0h Applied Voltage: Rated voltage Exposure Time: 24±2h at room condition*. • Pretreatment Perform a heat treatment at 150+0/-10°C for 1h±5min and then let sit for 24±2h at room condition*.
		Appearance	No defects or abnormalities.	Fix the capacitor to the supporting test substrate B (glass epoxy
		Capacitance Change	Within ±20%	 board) shown in "Complement of Test Method". Before this test, the test shown in the following is performed. No.11 Adhesive Strength of Termination (apply force: 5N)
		D.F.	0.05 max.	No.12 Substrate Bending Test
		I.R.	3000MΩ or more	Next, Impulse Voltage test is performed. Each individual capacitor shall be subjected to a 2.5kV Impulse
15	Durability	Voltage Proof	No defects.	Then the capacitor share be subjected to a 2.3 kV impulse (the voltage value means zero to peak) for 3 times. Then the capacitors are applied to life test. 100 (%) 90

* Room Condition: Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmosphere pressure: 86 to 106kPa

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GA3 Series Type GB Specifications and Test Methods (1)

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	Item	Specification	Test Method (Ref. Standard: JIS C 5101, IEC60384)
16	Passive Flammability	The burning time shall not be exceeded the time 30s. The tissue paper shall not ignite.	The capacitor under test shall be held in the flame in the position which best promotes burning. Each specimen shall only be exposed once to the flame. Time of exposure to flame: 30s Length of flame: 12±1mm Gas burner: Length 35mm min. Inside dia: 0.5±0.1mm Outside dia: 0.9mm max. Gas: Butane gas purity 95% min. Approximately 8mm Buner Flame Tissue Paper Wood Board of Approximately 10mm in Thickness
17	Active Flammability	The cheesecloth shall not be on fire.	The specimens shall be individually wrapped in at least one but more than two complete layers of cheesecloth. The specimens shall be subjected to 20 discharges. The interval between successive discharges shall be 5s. The UAC shall be maintained for 2min after the last discharge. $s_{1}^{1} = 1 + 1 + 1 + 1 + 1 + 1 + 1 + 1 + 1 + 1$

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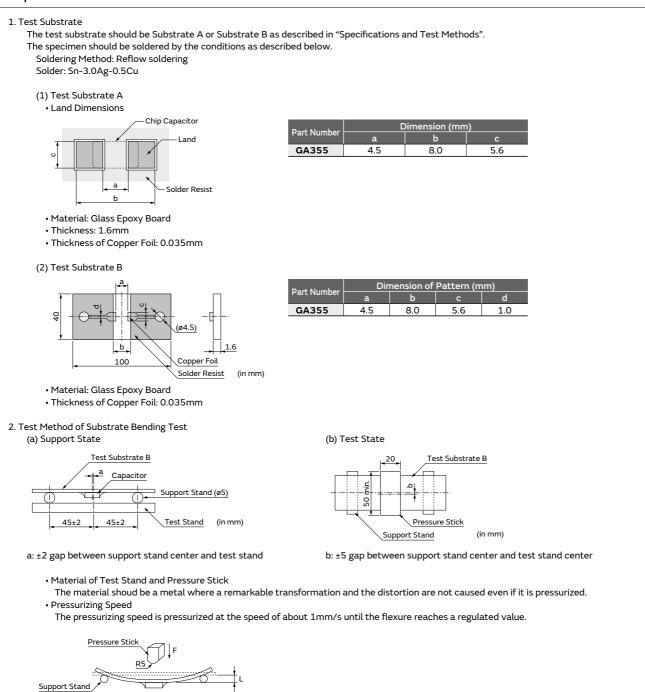
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GA3 Series Type GB Specifications and Test Methods (1)

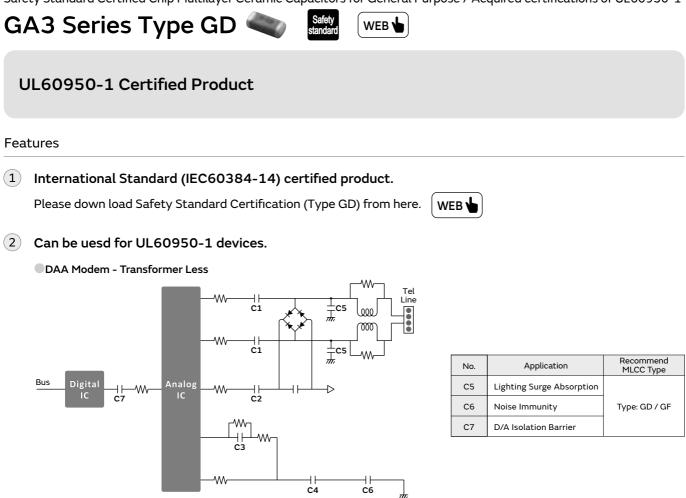
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Complement of Test Method



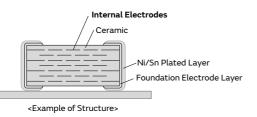
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Safety Standard Certified Chip Multilayer Ceramic Capacitors for General Purpose / Acquired certifications of UL60950-1



3 Realized large capacitance value and small size while maintaining high withstand voltages by the multilayer structure.

GND



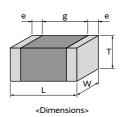
4 This product is only for reflow soldering.

Specifications

Size (mm)	4.5×2.0mm to 4.5×3.2mm
Rated Voltage	250Vac
Capacitance	10pF to 4700pF
Main Applications	Modem

This catalog contains only a portion of the product lineup.

Please refer to the capacitor search tool on the Murata Web site for details.



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GA3 Series Type GD Temperature Compensating Type 🎰 Part Number List

4.5×2.0mm

T max.	Rated Voltage	TC Code	Cap.	Tol.	Part Number	P*
1.0mm	250Vac	SL	10pF	±5%	GA342A1XGD100JW31#	p199
			12pF	±5%	GA342A1XGD120JW31#	p199
			15pF	±5%	GA342A1XGD150JW31#	p199
			18pF	±5%	GA342A1XGD180JW31#	p199
			22pF	±5%	GA342A1XGD220JW31#	p199
			27pF	±5%	GA342A1XGD270JW31#	p199
			33pF	±5%	GA342A1XGD330JW31#	p199
			39pF	±5%	GA342A1XGD390JW31#	p199
			47pF	±5%	GA342A1XGD470JW31#	p199
			56pF	±5%	GA342A1XGD560JW31#	p199
			68pF	±5%	GA342A1XGD680JW31#	p199
			82pF	±5%	GA342A1XGD820JW31#	p199

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GA3 Series Type GD High Dielectric Constant Type 📟 Part Number List

4.5×2.0mm

T max.	Rated Voltage	TC Code	Cap.	Tol.	Part Number	р*
1.5mm	250Vac	X7R	100pF	±10%	GA342QR7GD101KW01#	p203
			150pF	±10%	GA342QR7GD151KW01#	p203
			220pF	±10%	GA342QR7GD221KW01#	p203
			330pF	±10%	GA342QR7GD331KW01#	p203
			470pF	±10%	GA342QR7GD471KW01#	p203
			680pF	±10%	GA342QR7GD681KW01#	p203
			1000pF	±10%	GA342QR7GD102KW01#	p203
			1500pF	±10%	GA342QR7GD152KW01#	p203

4.5×3.2mm

T max.	Rated Voltage	TC Code	Cap.	Tol.	Part Number	р*
1.5mm	250Vac	X7R	1800pF	±10%	GA343QR7GD182KW01#	p203
			2200pF	±10%	GA343QR7GD222KW01#	p203
2.0mm	250Vac	X7R	4700pF	±10%	GA343DR7GD472KW01#	p203

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GA3 Series Type GD Specifications and Test Methods (1)

No	Ite	em	Specification	Test Method (Ref. Standard: JIS C 5101, IEC60384)	
1	Appearance		No defects or abnormalities.	Visual inspection.	
2	Dimension		Within the specified dimensions.	Using calipers and micrometers.	
3	Voltage Proof		No defects or abnormalities.	Measurement Point: Between the terminations Test Voltage: AC1500V (r.m.s.) Applied Time: 60±1s Charge/discharge current: 50mA max.	
4	Impulse Volta	ge	No self healing break downs or flash-overs have taken place in the capacitor.	10 impulse of alternating polarity is subjected. (5 impulse for each polarity) The interval between impulse is 60s. Applied Voltage: 2.5kVo-p	
5	Insulation Res	sistance (I.R.)	6000MΩ or more	Measurement Point: Between the terminations Measurement Voltage: DC500±50V Charging Time: 60±5s Measurement Temperature: Room Temperature	
6	Capacitance		Shown in Rated value.		
7	Q		C ≧ 30pF: 1000 or more C < 30pF: 400+20C or more C: Nominal Capacitance (pF)	- Measurement Temperature: Room Temperature Measurement Frequency: 1.0±0.1MHz Measurement Voltage: AC1.0±0.2V (r.m.s.)	
8	Temperature Characteristics of Capacitance		1X: +350 to -1000 ppm/°C (Temp.Range:+20 to +85°C)	The capacitance change should be measured after 5 minutes at each specified temp. stage. Capacitance value as a reference is the value in step 3. Step Temperature (°C) 1 Reference Temp. ±2 2 Min. Operating Temp. ±3 3 Reference Temp. ±2 4 Max. Operating Temp. ±3 5 Reference Temp. ±2 However, the capacitance shall be measured at even 85°C between step 3 and step 4.	
		Appearance	No defects or abnormalities.	Solder the capacitor on the test substrate A shown in	
		Capacitance	Within the specified initial value.	"Complement of Test Method". Kind of Vibration: A simple harmonic motion	
9	Vibration	Q	Within the specified initial value.	10Hz to 55Hz to 10Hz (1min) Total amplitude: 1.5mm This motion should be applied for a period of 2h in each 3 mutually perpendicular directions (total of 6h).	
10	Solderability		95% of the terminations is to be soldered evenly and continuously.	Test Method: Solder bath method Flux: Solution of rosin ethanol 25 (wt)% Preheat: 80 to 120°C for 10 to 30s Solder: Sn-3.0Ag-0.5Cu (Lead Free Solder) Solder Temp:: 245±5°C Immersion time: 2±0.5s Immersing in speed: 25±2.5mm/s.	
		Appearance	No defects or abnormalities.	Test Method: Solder bath method	
	Resistance to	Capacitance Change	Within±2.5% or ±0.25pF (Whichever is larger)	Solder: Sn-3.0Ag-0.5Cu (Lead Free Solder) Solder Temp.: 260±5°C Immersion time: 10±1s	
11	Soldering	I.R.	1000M Ω or more	Immersing in speed: 25±2.5mm/s.	
	Heat Voltage Proof		No defects.	Exposure Time: 24±2h at room condition*. Preheat: GA342 size: 100 to 120°C for 1min and 170 to 200°C for 1min	
12	2 Adhesive Strength of Termination		No removal of the terminations or other defect should occur.	Solder the capacitor on the test substrate A shown in "Complement of Test Method". ION, 10±1s Applied Direction: In parallel with the test substrate and vertical with the capacitor side.	
13	3 Substrate Bending Test		No defects or abnormalities.	Solder the capacitor on the test substrate B shown in "Complement of Test Method". Then apply the force in the direction shown in "Test Method of Substrate Bending Test" of "Complement of Test Method". Flexure: 1mm Holding Time: 5±1s Soldering Method: Reflow soldering	

* Room Condition: Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmosphere pressure: 86 to 106kPa

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GA3 Series Type GD Specifications and Test Methods (1)

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No	lte	em	Specification	Test Method (Ref. Standard: JIS C 5101, IEC60384)
		Appearance Capacitance Change	No defects or abnormalities. Within ±2.5% or ±0.25pF (Whichever is larger)	Fix the capacitor to the supporting test substrate A (glass epoxy board) shown in "Complement of Test Method" Perform the 5 cycles according to the four heat treatments shown in the following table.
	Temperature	Q	Within the specified initial value.	Step Temp. (°C) Time (min)
14	Sudden Change	I.R. Voltage Proof	3000MΩ or more No defects.	1 Min. Operating Temp. +0/-3 30±3 2 Room Temp. 2 to 3 3 Max. Operating Temp. +3/-0 30±3 4 Room Temp. 2 to 3 Exposure Time: 24±2h at room condition*.
		Appearance	No defects or abnormalities.	
	High	Capacitance Change	Within ±5.0% or ±0.5pF (Whichever is larger)	Fix the capacitor to the supporting test substrate B (glass epoxy board) shown in "Complement of Test Method".Before this test, the test shown in the following is performed.
15	Temperature High Humidity (Steady)	Q	C ≧ 30pF: 350 or more C < 30pF: 275+5/2C or more C: Nominal Capacitance (pF)	 No.12 Adhesive Strength of Termination (apply force: 5N) No.13 Substrate Bending Test Test Temperature: 40±2°C Test Humidity: 90 to 95%RH
	(Steady)	I.R.	3000MΩ or more	Test Time: 500+24/-0h.
		Voltage Proof	No defects.	Applied Voltage: Rated voltage Exposure Time:24±2h at room condition*.
		Appearance	No defects or abnormalities.	Fix the capacitor to the supporting test substrate B (glass epoxy
		Capacitance Change	Within ±3.0% or ±0.3pF (Whichever is larger)	 board) shown in "Complement of Test Method". Before this test, the test shown in the following is performed. • No.12 Adhesive Strength of Termination (apply force: 5N)
		Q	C ≧ 30pF: 350 or more C < 30pF: 275+5/2C or more C: Nominal Capacitance (pF)	No.13 Substrate Bending Test Next, Impulse Voltage test is performed. Each individual capacitor shall be subjected to a 2.5kV Impulse
		I.R.	3000MΩ or more	 (the voltage value means zero to peak) for 3 times. Then the capacitors are applied to life test.
16	Durability	Voltage Proof	No defects.	$\begin{array}{c} 100 \ (\%) \\ 90 \\ \hline 50 \\ 0 \\ \hline 1 \\ 1 \\$
				Applied voltage AC425V (r.m.s.), except that once each hour the voltage is increased to AC1000V (r.m.s.) for 0.1s. Exposure Time: 24±2h at room condition*.
17	Passive Flamr	nability	The burning time shall not be exceeded the time 30s. The tissue paper shall not ignite.	The capacitor under test shall be held in the flame in the position which best promotes burning. Each specimen shall only be exposed once to the flame. Time of exposure to flame: 30s Length of flame: 12±1mm Gas burner: Length 35mm min. Inside dia: 0.5±0.1mm Outside dia: 0.9mm max. Gas: Butane gas purity 95% min. Approximately 8mm Buner Flame Loot 5mm Test Specimen Test Specimen Tissue Paper
				Wood Board of Approximately 10mm in Thickness
* D		Tama anatuma, 1	.5 to 35°C. Relative humidity: 45 to 75%. Atmosphere pr	

* Room Condition: Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmosphere pressure: 86 to 106kPa

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∕∆Note	• Please read rating and 🖄 CAUTION (for storage, operating, rating, soldering, mounting and handling) in this catalog to prevent smoking and/or burning, etc.
	This catalog has only typical specifications. Therefore, please approve our product specifications or transact the approval sheet for product specifications before ordering.

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GA3 Series Type GD Specifications and Test Methods (1)

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Item	Specification	Test Method (Ref. Standard: JIS C 5101, IEC60384)
		The specimens shall be individually wrapped in at least one but more than two complete layers of cheesecloth. The specimens shall be subjected to 20 discharges. The interval between successive discharges shall be 5s. The UAC shall be maintained for 2min after the last discharge. $S_{1} = \underbrace{r_{1}}_{Tr} \underbrace{r_{2}}_{U_{1}} \underbrace{r_{1}}_{U_{2}} \underbrace{r_{2}}_{U_{2}} \underbrace{r_{1}}_{U_{2}} \underbrace{r_{2}}_{U_{2}} \underbrace{r_{2}}$
		C1, C2: Filter capacitor 1µF±10% C3: Capacitor 0.033µF±5%
Active Flammability	The cheesecloth shall not be on fire.	L1 to L4: Rod coa choke 1.5mH±20%, 16A R: Resistor $100\Omega\pm2\%$ Cx < 0.068μ F Ct: Tank capacitor 3μ F±5% 10kV Cx $\leq 1\mu$ F U-: UR±5% UR: Rated voltage Cx: Capacitor under test F: Slow-blow fuse, rated 16A Ut: Voltage to which the tank capacitor Ct is charged Ux 2.5kV time

GA3 Series Type GD Specifications and Test Methods (1)

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Complement of Test Method

1. Test Substrate

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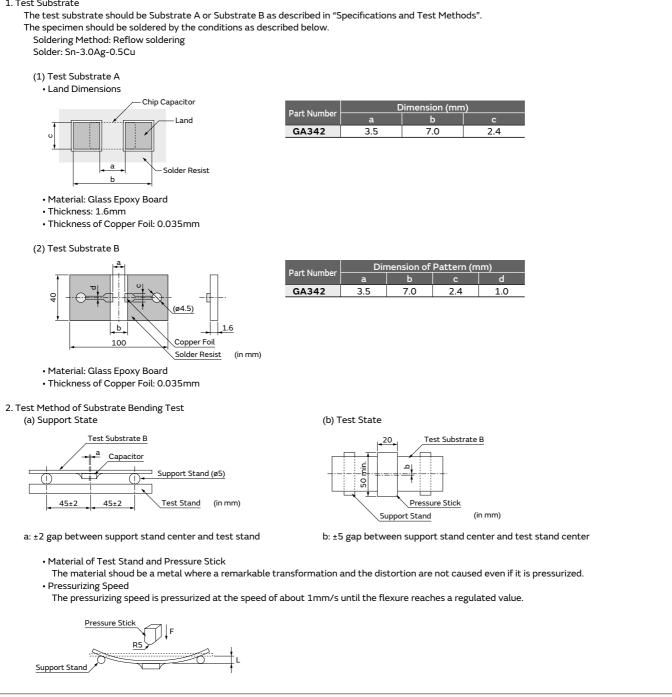
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GA3 Series Type GD Specifications and Test Methods (2)

No		em	Specification	Tort Mathed (Daf Standard, US C F101 (FCC0204)
		em	Specification	Test Method (Ref. Standard: JIS C 5101, IEC60384)
1	Appearance Dimension		No defects or abnormalities.	Visual inspection.
3	Voltage Proof		Within the specified dimensions. No defects or abnormalities.	Using calipers and micrometers. Measurement Point: Between the terminations Test Voltage: AC1500V (r.m.s.) Applied Time: 60±1s Charge/discharge current: 50mA max.
4	Impulse Voltage		No self healing break downs or flash-overs have taken place in the capacitor.	10 impulse of alternating polarity is subjected. (5 impulse for each polarity) The interval between impulse is 60s. Applied Voltage: 2.5kVo-p
5	Insulation Re	sistance (I.R.)	6000MΩ or more	Measurement Point: Between the terminations Measurement Voltage: DC500±50V Charging Time: 60±5s Measurement Temperature: Room Temperature
6	Capacitance		Shown in Rated value.	Measurement Temperature: Room Temperature
7	Dissipation Fa	actor (D.F.)	0.025 max.	Measurement Frequency: 1.0±0.1kHz Measurement Voltage: AC1.0±0.2V (r.m.s.)
8	Temperature Characteristics of Capacitance		R7: Within ±15% (-55 to +125°C)	The capacitance change should be measured after 5 minutes at each specified temp. stage. Capacitance value as a reference is the value in step 3. Step Temperature (°C) 1 Reference Temp. ±2 2 Min. Operating Temp. ±3 3 Reference Temp. ±2 4 Max. Operating Temp. ±3 5 Reference Temp. ±2 4 Max. Operating Temp. ±3 5 Reference Temp. ±2 end Max. Operating Temp. ±3 5 Reference Temp. ±2
			No de Carlo en altre en altre a	then let sit for 24±2h at room condition*.
	Appearance		No defects or abnormalities.	Solder the capacitor on the test substrate A shown in "Complement of Test Method".
9	Vibration	Capacitance D.F.	Within the specified initial value. Within the specified initial value.	Kind of Vibration: A simple harmonic motion 10Hz to 55Hz to 10Hz (1min) Total amplitude: 1.5mm This motion should be applied for a period of 2h in each 3 mutually perpendicular directions (total of 6h).
10	Solderability		95% of the terminations is to be soldered evenly and continuously.	Test Method: Solder bath method Flux: Solution of rosin ethanol 25 (wt)% Preheat: 80 to 120°C for 10 to 30s Solder: Sn-3.0Ag-0.5Cu (Lead Free Solder) Solder Temp.: 245±5°C Immersion time: 2±0.5s Immersing in speed: 25±2.5mm/s.
		Appearance	No defects or abnormalities.	Test Method: Solder bath method
		Capacitance Change	Within ±10%	Solder: Sn-3.0Ag-0.5Cu (Lead Free Solder) Solder Temp.: 260±5°C Immersion time: 10±1s
	Resistance to	I.R.	1000MΩ or more	Immersing in speed: 25±2.5mm/s.
11	Soldering Heat	Voltage Proof No defects.	No defects.	Exposure Time: 24±2h at room condition*. Preheat: GA342/43 size: 100 to 120°C for 1min and 170 to 200°C for 1min • Pretreatment Perform a heat treatment at 150+0/-10°C for 1h±5min and then let sit for 24±2h at room condition*.
12	Adhesive Strength of Termination		No removal of the terminations or other defect should occur.	Solder the capacitor on the test substrate A shown in "Complement of Test Method". 10N, 10±1s Applied Direction: In parallel with the test substrate and vertical with the capacitor side.

* Room Condition: Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmosphere pressure: 86 to 106kPa

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ACaution /Notice

GA3 Series Type GD Specifications and Test Methods (2)

Continued from the preceding page. $oldsymbol{\lambda}$

No	lte	m	Specification	Test Method (Ref. Standard: JIS C 5101, IEC60384)
13	Substrate Bending Test		No defects or abnormalities.	Solder the capacitor on the test substrate B shown in "Complement of Test Method". Then apply the force in the direction shown in "Test Method of Substrate Bending Test" of "Complement of Test Method" Flexure: 1mm Holding Time: 5±1s Soldering Method: Reflow soldering
		Appearance	No defects or abnormalities.	Fix the capacitor to the supporting test substrate A (glass epox
		Capacitance Change	Within±15%	board) shown in "Complement of Test Method". Perform the 5 cycles according to the four heat treatments shown in the following table.
		D.F.	0.05 max.	Step Temp. (°C) Time (min)
	Temperature	I.R.	3000MΩ or more	1 Min. Operating Temp. +0/-3 30±3
14	Sudden Change	Voltage Proof	No defects.	2 Room Temp. 2 to 3 3 Max. Operating Temp. +3/-0 30±3 4 Room Temp. 2 to 3 Exposure Time: 24±2h at room condition*. Pretreatment Perform a heat treatment at 150+0/-10°C for 1h±5min and then let sit for 24±2h at room condition*.
		Appearance	No defects or abnormalities.	Fix the capacitor to the supporting test substrate B (glass epox
	High Temperature High Humidity (Steady)	Capacitance Change	Within±15%	board) shown in "Complement of Test Method". Before this test, the test shown in the following is performed. • No.12 Adhesive Strength of Termination (apply force: 5N)
		D.F.	0.05 max.	No.13 Substrate Bending Test
15		I.R.	3000MΩ or more	Test Temperature: 40±2°C Test Humidity: 90 to 95%RH
		Voltage Proof	No defects.	Test Time: 500+24/-0h Applied Voltage: Rated voltage Exposure Time: 24±2h at room condition*. • Pretreatment Perform a heat treatment at 150+0/-10°C for 1h±5min and then let sit for 24±2h at room condition*.
		Appearance	No defects or abnormalities.	Fix the capacitor to the supporting test substrate B (glass epox
		Capacitance Change	Within ±20%	board) shown in "Complement of Test Method". Before this test, the test shown in the following is performed. • No.12 Adhesive Strength of Termination (apply force: 5N)
		D.F.	0.05 max.	No.13 Substrate Bending Test
		I.R.	3000MΩ or more	Next, Impulse Voltage test is performed. Each individual capacitor shall be subjected to a 2.5kV Impulse
16	Durability	Voltage	No defects.	(the voltage value means zero to peak) for 3 times. Then the capacitors are applied to life test. 100 (%) 90 50 50 100 (%) 100 (%) 100 (%) 100
			Proof	

* Room Condition: Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmosphere pressure: 86 to 106kPa

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GA3 Series Type GD Specifications and Test Methods (2)

Continued from the preceding page. ${\bf \searrow}$

more than two complete layers of cheesecloth. The specimens shall be subjected to 20 discharges. The interval between successive discharges shall be 5s.	No	ltem	Specification	Test Method (Ref. Standard: JIS C 5101, IEC60384)
18 Active Flammability The cheesecloth shall not be on fire. C1, C2: Filter capacitor 1µF±10% C3: Capacitor 0.033µF±5% UL to L4: Rod coa choke 1.5mH±20%, 16A R: Resistor 100Ω±2% Cx < 0.068µF C4: Tank capacitor 3µF±5% 10kV Cx ≤ 1µF U-: UR±5% UR: Rated voltage 	17	Passive Flammability		position which best promotes burning. Each specimen shall only be exposed once to the flame. Time of exposure to flame: 30s Length of flame: 12±1mm Gas burner: Length 35mm min. Inside dia: 0.5±0.1mm Outside dia: 0.9mm max. Gas: Butane gas purity 95% min. Approximately 8mm Buner Hame Z00±5mm Tissue Paper
	18	Active Flammability	The cheesecloth shall not be on fire.	The specimens shall be subjected to 20 discharges. The interval between successive discharges shall be 5s. The UAC shall be maintained for 2min after the last discharge. $S_{1}^{I} \xrightarrow{F} L_{1}^{I} \xrightarrow{L_{2}^{I}} C_{1}^{I} \xrightarrow{C_{1}^{I}} C_{2}^{I} C_{1$

GA3 Series Type GD Specifications and Test Methods (2)

Continued from the preceding page.

Complement of Test Method

1. Test Substrate

The test substrate should be Substrate A or Substrate B as described in "Specifications and Test Methods". The specimen should be soldered by the conditions as described below. Soldering Method: Reflow soldering Solder: Sn-3.0Ag-0.5Cu (1) Test Substrate A Land Dimensions Chip Capacitor Dimension (mm) Part Numbe а - Land GA342 7.0 3.5 2.4 3.5 7.0 3.7 GA343 a Solder Resist

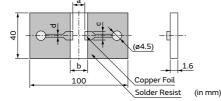
• Material: Glass Epoxy Board

- Thickness: 1.6mm
- Thickness of Copper Foil: 0.035mm



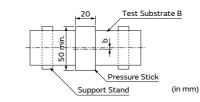
(a) Support State

45±2



Part Number	Dir	ım)		
Part Number	a	b	с	d
GA342	3.5	7.0	2.4	1.0
GA343	3.5	7.0	3.7	1.0

(b) Test State



b: ±5 gap between support stand center and test stand center

Material of Test Stand and Pressure Stick

a: ± 2 gap between support stand center and test stand

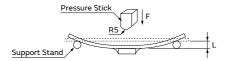
Support Stand (ø5)

(in mm)

Test Stand

The material shoud be a metal where a remarkable transformation and the distortion are not caused even if it is pressurized. Pressurizing Speed

The pressurizing speed is pressurized at the speed of about 1mm/s until the flexure reaches a regulated value.



• Material: Glass Epoxy Board Thickness of Copper Foil: 0.035mm 2. Test Method of Substrate Bending Test Test Substrate B apacitor 45±2

Safety Standard Certified Chip Multilayer Ceramic Capacitors for General Purpose / Acquired certifications of IEC60384-14 Class X1/Y2 and UL60950-1

GA3 Series Type GF 🔍

WEB 🖕

Size 4.5x2.0mm: This product is applicable only for the instruments certified by EN/IEC60950-1

Safety

Size 5.7x2.8mm or 5.7x5.0mm: This product is applicable as X or Y capacitor

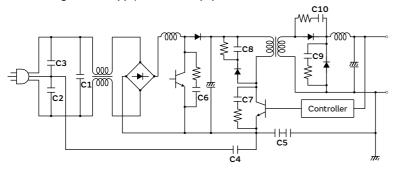
Features

1 International Standard (IEC60384-14) certified product.

Please down load Safety Standard Certification (Type GF: X1/Y2) from here.

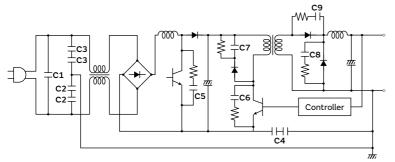
2 Can be used as a Class Y2 capacitor.

Switching Power Supply - Class 1 Equipment



No.	Application	Recommend MLCC Type
C1	X Cap	Type: GB
C2		
С3	Y Cap	Type: GF
C4		
C5	Primary - Secondary Coupling	Type: GF×2

Switching Power Supply - Class 2 Equipment



No.	Application	Recommend MLCC Type	
C1	X Cap	Type: GB	
C2	¥ 6		
С3	Y Cap	Type: GF×2	
C4	Primary - Secondary Coupling		

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GD GA3

GF GF

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KRM

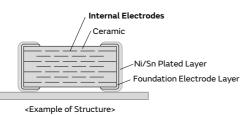
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①Caution
/Notice

Realized large capacitance value and small size while maintaining high withstand voltages by the multilayer structure.



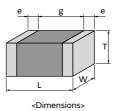
4 This product is only for reflow soldering.

Specifications

Size (mm)	4.5×2.0mm to 5.7×5.0mm
Rated Voltage	250Vac
Capacitance	10pF to 4700pF
Main Applications	AC-DC power supply

This catalog contains only a portion of the product lineup.

Please refer to the capacitor search tool on the Murata Web site for details.



GA3 Series Type GF Temperature Compensating Type 📟 Part Number List

4.5×2.0mm

T max.	Rated Voltage	TC Code	Cap.	Tol.	Part Number	р*
1.0mm	250Vac	SL	10pF	±5%	GA342A1XGF100JW31#	p211
			12pF	±5%	GA342A1XGF120JW31#	p211
			15pF	±5%	GA342A1XGF150JW31#	p211
			18pF	±5%	GA342A1XGF180JW31#	p211
			22pF	±5%	GA342A1XGF220JW31#	p211
			27pF	±5%	GA342A1XGF270JW31#	p211
			33pF	±5%	GA342A1XGF330JW31#	p211
			39pF	±5%	GA342A1XGF390JW31#	p211
			47pF	±5%	GA342A1XGF470JW31#	p211
			56pF	±5%	GA342A1XGF560JW31#	p211
			68pF	±5%	GA342A1XGF680JW31#	p211
			82pF	±5%	GA342A1XGF820JW31#	p211

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ACaution /Notice

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GA3 Series Type GF High Dielectric Constant Type 📟 Part Number List

4.5×2.0mm

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T max.	Rated Voltage	TC Code	Cap.	Tol.	Part Number	P*
1.5mm	250Vac	X7R	100pF	±10%	GA342QR7GF101KW01#	p215
			150pF	±10%	GA342QR7GF151KW01#	p215
			470pF	±10%	GA342QR7GF471KW01#	p215
			680pF	±10%	GA342QR7GF681KW01#	p215
2.2mm	250Vac	X7R	220pF	±10%	GA342DR7GF221KW02#	p215
			330pF	±10%	GA342DR7GF331KW02#	p215
			1000pF	±10%	GA342DR7GF102KW02#	p215

5.7×2.8mm

T max.	Rated Voltage	TC Code	Cap.	Tol.	Part Number	р*
1.5mm	250Vac	X7R	100pF	±10%	GA352QR7GF101KW31#	p215
			150pF	±10%	GA352QR7GF151KW31#	p215
			220pF	±10%	GA352QR7GF221KW31#	p215
			330pF	±10%	GA352QR7GF331KW31#	p215
			470pF	±10%	GA352QR7GF471KW01#	p215
			680pF	±10%	GA352QR7GF681KW01#	p215
			1000pF	±10%	GA352QR7GF102KW01#	p215
			1500pF	±10%	GA352QR7GF152KW01#	p215

5.7×5.0mm

T max.	Rated Voltage	TC Code	Cap.	Tol.	Part Number	P*
1.5mm	250Vac	X7R	1800pF	±10%	GA355QR7GF182KW01#	p215
			2200pF	±10%	GA355QR7GF222KW01#	p215
			3300pF	±10%	GA355QR7GF332KW01#	p215
2.0mm	250Vac	X7R	4700pF	±10%	GA355DR7GF472KW01#	p215



GA3 Series Type GF Specifications and Test Methods (1)

No	lte	em	Specification	Test Method (Ref. Standard: JIS C 5101, IEC60384)
1	Appearance		No defects or abnormalities.	Visual inspection.
2			Within the specified dimensions.	Using calipers and micrometers.
3			No defects or abnormalities.	Measurement Point: Between the terminations Test Voltage: AC2000V (r.m.s.) Applied Time: 60±1s Charge/discharge current: 50mA max.
4	Impulse Voltage		No self healing break downs or flash-overs have taken place in the capacitor.	10 impulse of alternating polarity is subjected. (5 impulse for each polarity) The interval between impulse is 60s. Applied Voltage: 2.5kVo-p
5	Insulation Resistance (I.R.)		6000MΩ or more	Measurement Point: Between the terminations Measurement Voltage: DC500±50V Charging Time: 60±5s Measurement Temperature: Room Temperature
6	Capacitance		Shown in Rated value.	
C ≥ 30pF: 1000 or more Measurement Temperature: Room Tempe C ≥ 30pF: 1000 or more Measurement Frequency: 1.0±0.1MHz		· · ·		
8	Temperature Characteristics of Capacitance		1X: +350 to -1000 ppm/°C (Temp.Range:+20 to +85°C)	The capacitance change should be measured after 5 minutes at each specified temp. stage. Capacitance value as a reference is the value in step 3. Step Temperature (°C) 1 Reference Temp. ±2 2 Min. Operating Temp. ±3 3 Reference Temp. ±2 4 Max. Operating Temp. ±3 5 Reference Temp. ±2 However, the capacitance shall be measured at even 85°C between step 3 and step 4.
		Appearance	No defects or abnormalities.	Solder the capacitor on the test substrate A shown in
9	Capacitance Vibration Q		Within the specified initial value. Within the specified initial value.	"Complement of Test Method". Kind of Vibration: A simple harmonic motion 10Hz to 55Hz to 10Hz (1min) Total amplitude: 1.5mm This motion should be applied for a period of 2h in each 3 mutually perpendicular directions (total of 6h).
10) Solderability		95% of the terminations is to be soldered evenly and continuously.	Test Method: Solder bath method Flux: Solution of rosin ethanol 25 (wt)% Preheat: 80 to 120°C for 10 to 30s Solder: Sn-3.0Ag-0.5Cu (Lead Free Solder) Solder Temp.: 245±5°C Immersion time: 2±0.5s Immersing in speed: 25±2.5mm/s.
		Appearance	No defects or abnormalities.	Test Method: Solder bath method
	Resistance to	Capacitance Change	Within±2.5% or ±0.25pF (Whichever is larger)	Solder: Sn-3.0Ag-0.5Cu (Lead Free Solder) Solder Temp.: 260±5°C Immersion time: 10±1s
11	Soldering	I.R.	1000MΩ or more	Immersing in speed: 25±2.5mm/s.
	Heat Voltage Proof		No defects.	Exposure Time: 24±2h at room condition*. Preheat: GA342 size: 100 to 120°C for 1min and 170 to 200°C for 1min
12	2 Adhesive Strength of Termination		No removal of the terminations or other defect should occur.	Solder the capacitor on the test substrate A shown in "Complement of Test Method". ION, 10±1s Applied Direction: In parallel with the test substrate and vertical with the capacitor side.
13	3 Substrate Bending Test		No defects or abnormalities.	Solder the capacitor on the test substrate B shown in "Complement of Test Method". Then apply the force in the direction shown in "Test Method of Substrate Bending Test" of "Complement of Test Method". Flexure: 1mm Holding Time: 5±1s Soldering Method: Reflow soldering

* Room Condition: Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmosphere pressure: 86 to 106kPa

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GA3 Series Type GF Specifications and Test Methods (1)

Continued from the preceding page. \searrow

No	lte	em	Specification	Test Method (Ref. Standard: JIS C 5101, IEC60384)
		Appearance Capacitance	No defects or abnormalities.	Fix the capacitor to the supporting test substrate A (glass epoxy board) shown in "Complement of Test Method". Perform the 5 cycles according to the four heat treatments
	_	Change	Within ±2.5% or ±0.25pF (Whichever is larger)	shown in the following table.
14	Temperature Sudden	Q I.R.	Within the specified initial value. 3000MΩ or more	Step Temp. (°C) Time (min) 1 Min. Operating Temp. +0/-3 30±3
	Change	Voltage Proof	No defects.	1 1
		Appearance	No defects or abnormalities.	
	11:	Capacitance Change	Within ±5.0% or ±0.5pF (Whichever is larger)	Fix the capacitor to the supporting test substrate B (glass epoxy board) shown in "Complement of Test Method". Before this test, the test shown in the following is performed.
15	High Temperature High Humidity (Steady)	Q	C ≧ 30pF: 350 or more C < 30pF: 275+5/2C or more C: Nominal Capacitance (pF)	 No.12 Adhesive Strength of Termination (apply force: 5N) No.13 Substrate Bending test Test Temperature: 40±2°C Test Humidity: 90 to 95%RH
	(Steady)	I.R.	3000MΩ or more	Test Time: 500+24/-0h Applied Voltage: Rated voltage
		Voltage Proof	No defects.	Exposure Time: 24±2h at room condition*.
		Appearance	No defects or abnormalities.	Fix the capacitor to the supporting test substrate B (glass epoxy
		Capacitance Change	Within ±3.0% or ±0.3pF (Whichever is larger)	 board) shown in "Complement of Test Method". Before this test, the test shown in the following is performed. • No.12 Adhesive Strength of Termination (apply force: 5N)
		Q	C ≧ 30pF: 350 or more C < 30pF: 275+5/2C or more C: Nominal Capacitance (pF)	No.13 Substrate Bending test Next, Impulse Voltage test is performed. Each individual capacitor shall be subjected to a 5kV Impulse
		I.R.	3000MΩ or more	(the voltage value means zero to peak) for 3 times. Then the capacitors are applied to life test.
16	Durability	Urability Voltage Proof No defects.	No defects.	Front time (T1) = 1.2μ s= $1.67T$ Time to half-value (T2) = 50μ s
			Apply voltage as Table for 1000h at 125+2/-0°C , relative humidity 50% max. Applied voltage AC425V (r.m.s.), except that once each hour the voltage is increased to AC1000V (r.m.s.) for 0.1s. Exposure Time: 24±2h at room condition*.	
17	7 Passive Flammability		The burning time shall not be exceeded the time 30s. The tissue paper shall not ignite.	The capacitor under test shall be held in the flame in the position which best promotes burning. Each specimen shall only be exposed once to the flame. Time of exposure to flame: 30s Length of flame: 12±1mm Gas burner: Length 35mm min. Inside dia: 0.5±0.1mm Outside dia: 0.9mm max. Gas: Butane gas purity 95% min. Approximately 8mm Buner - Flame 45° - Tissue Paper
				1
				Wood Board of Approximately 10mm in Thickness

* Room Condition: Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmosphere pressure: 86 to 106kPa

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∕∆Note	• Please read rating and ACAUTION (for storage, operating, rating, soldering, mounting and handling) in this catalog to prevent smoking and/or burning, etc.
	This catalog has only typical specifications. Therefore, please approve our product specifications or transact the approval sheet for product specifications before ordering.

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GA3 Series Type GF Specifications and Test Methods (1)

Continued from the preceding page. $oldsymbol{\searrow}$

No	ltem	Specification	Test Method (Ref. Standard: JIS C 5101, IEC60384)
18	Active Flammability	The cheesecloth shall not be on fire.	The specimens shall be individually wrapped in at least one but more than two complete layers of cheesecloth. The specimens shall be subjected to 20 discharges. The interval between successive discharges shall be 5s. The UAC shall be maintained for 2min after the last discharge. $\underbrace{S1}_{Tr} \underbrace{c1}_{Tr} \underbrace{c1}_{C1} \underbrace{c2}_{C2} \underbrace{c3}_{Cx} \underbrace{cx}_{Tr} \underbrace{c1}_{C1} \underbrace{c1}_{C2} \underbrace{c3}_{Cx} \underbrace{cx}_{Tr} \underbrace{c1}_{C1} \underbrace{c1}_{C2} \underbrace{c3}_{Cx} \underbrace{c1}_{C1} \underbrace{c1}_{C2} \underbrace{c3}_{Cx} \underbrace{c1}_{C1} \underbrace{c1}_{C2} \underbrace{c3}_{Cx} \underbrace{c1}_{C1} \underbrace{c1}_{C2} \underbrace{c3}_{Cx} \underbrace{c1}_{C1} \underbrace{c1}_{C1} \underbrace{c1}_{C2} \underbrace{c3}_{C1} \underbrace{c1}_{C1} \underbrace{c1}_{C2} \underbrace{c1}_{C1} \underbrace{c1}_{C2} \underbrace{c3}_{C1} \underbrace{c1}_{C1} c1$
			R: Resistor $100\Omega \pm 2\%$ Cx < 0.068μ F Ct: Tank capacitor 3μ F $\pm 5\%$ 10kV Cx $\leq 1\mu$ F U-: UR $\pm 5\%$ UR: Rated voltage Cx: Capacitor under test F: Slow-blow fuse, rated 16A Ut: Voltage to which the tank capacitor Ct is charged

GA3 Series Type GF Specifications and Test Methods (1)

Continued from the preceding page.

Complement of Test Method

1. Test Substrate

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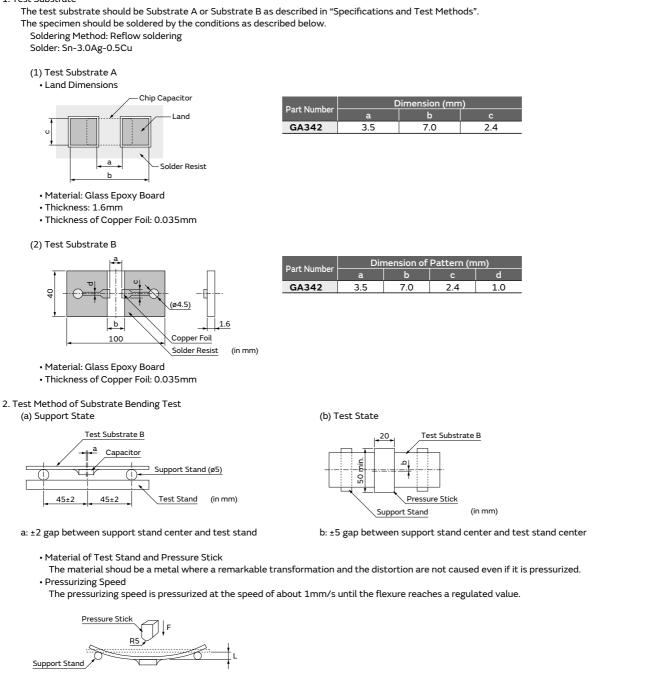
NFM

КВМ

KR3

GMA

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GA3 Series Type GF Specifications and Test Methods (2)

No	lte	em	Specification	Test Method (Ref. Standard: JIS C 5101, IEC60384)	
1	Appearance		No defects or abnormalities.	Visual inspection.	
2	Dimension		Within the specified dimensions.	Using calipers and micrometers.	
3	Voltage Proof		No defects or abnormalities.	Measurement Point: Between the terminations Test Voltage: AC2000V (r.m.s.) Applied Time: 60±1s Charge/discharge current: 50mA max.	
4	Impulse Voltage		No self healing break downs or flash-overs have taken place in the capacitor.	10 impulse of alternating polarity is subjected. (5 impulse for each polarity) The interval between impulse is 60s. Applied Voltage: 2.5kVo-p	
5	Insulation Resistance (I.R.)		6000MΩ or more	Measurement Point: Between the terminations Measurement Voltage: DC500±50V Charging Time: 60±5s Charge/discharge current: 50mA max. Measurement Temperature: Room Temperature	
6	Capacitance		Shown in Rated value.	Measurement Temperature: Room Temperature	
7	Dissipation Fa	actor (D.F.)	0.025 max.	Measurement Temperature: Room Temperature Measurement Frequency: 1.0±0.1kHz Measurement Voltage: AC1.0±0.2V (r.m.s.)	
8	Temperature Characteristics of Capacitance		R7: Within ±15% (-55 to +125°C)	The capacitance change should be measured after 5 minutes at each specified temp. stage. Capacitance value as a reference is the value in step 3. Step Temperature (°C) 1 Reference Temp. ±2 2 Min. Operating Temp. ±3 3 Reference Temp. ±2 4 Max. Operating Temp. ±3 5 Reference Temp. ±2 • Pretreatment Perform a heat treatment at 150+0/-10°C for 1h±5min and then let sit for 24±2h at room condition*.	
	Appearance Capacitance		No defects or abnormalities.	Solder the capacitor on the test substrate A shown in	
			Within the specified initial value.	Complement of Test Method". Kind of Vibration: A simple harmonic motion	
9	Vibration	D.F.	Within the specified initial value.	10Hz to 55Hz to 10Hz (1min) Total amplitude: 1.5mm This motion should be applied for a period of 2h in each 3 mutually perpendicular directions (total of 6h).	
10	Solderability		95% of the terminations is to be soldered evenly and continuously.	Test Method: Solder bath method Flux: Solution of rosin ethanol 25 (wt)% Preheat: 80 to 120°C for 10 to 30s Solder: Sn-3.0Ag-0.5Cu (Lead Free Solder) Solder Temp.: 245±5°C Immersion time: 2±0.5s Immersing in speed: 25±2.5mm/s.	
		Appearance	No defects or abnormalities.	Test Method: Solder bath method	
		Capacitance Change	Within ±10%	Solder: Sn-3.0Ag-0.5Cu (Lead Free Solder) Solder Temp.: 260±5°C Immersion time: 10±1s	
	Resistance to	I.R.	1000MΩ or more	Immersing in speed: 25±2.5mm/s.	
11	Soldering Heat	Voltage Proof	No defects.	Exposure Time: 24±2h at room condition*. Preheat: GA342/52/55 size: 100 to 120°C for 1min and 170 to 200°C for 1min • Pretreatment Perform a heat treatment at 150+0/-10°C for 1h±5min and then let sit for 24±2h at room condition*.	
12	2 Adhesive Strength of Termination		No removal of the terminations or other defect should occur.	Solder the capacitor on the test substrate A shown in "Complement of Test Method". ION, 10±1s Applied Direction: In parallel with the test substrate and vertical with the capacitor side.	

* Room Condition: Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmosphere pressure: 86 to 106kPa

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GMA

GMD

ACaution /Notice

GA3 Series Type GF Specifications and Test Methods (2)

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No	lte	m	Specification	Test Method (Ref. Standard: JIS C 5101, IEC60384)		
13	Substrate Bending Test		No defects or abnormalities.	Solder the capacitor on the test substrate B shown in "Complement of Test Method". Then apply the force in the direction shown in "Test Method of Substrate Bending Test" of "Complement of Test Method". Flexure: 1mm Holding Time: 5±1s Soldering Method: Reflow soldering		
		Appearance	No defects or abnormalities.	Fix the capacitor to the supporting test substrate A (glass epox		
		Capacitance Change	Within±15%	board) shown in "Complement of Test Method". Perform the 5 cycles according to the four heat treatments shown in the following table.		
		D.F.	0.05 max.	Step Temp. (°C) Time (min)		
	Temperature	I.R.	3000MΩ or more	1 Min. Operating Temp. +0/-3 30±3		
14	Sudden Change	Voltage Proof	No defects.	2 Room Temp. 2 to 3 3 Max. Operating Temp. +3/-0 30±3 4 Room Temp. 2 to 3 Exposure Time: 24±2h at room condition*. • Pretreatment Perform a heat treatment at 150+0/-10°C for 1h±5min and then let sit for 24±2h at room condition*.		
		Appearance	No defects or abnormalities.	Fix the capacitor to the supporting test substrate B (glass epox		
	High Temperature High Humidity (Steady)	Capacitance Change	Within±15%	board) shown in "Complement of Test Method". Before this test, the test shown in the following is performed. • No.12 Adhesive Strength of Termination (apply force: 5N)		
		D.F.	0.05 max.	No.13 Substrate Bending Test		
15		I.R.	3000MΩ or more	Test Temperature: 40±2°C Test Humidity: 90 to 95%RH		
		Voltage Proof	No defects.	Test Time: 500+24/-0h Applied Voltage: Rated voltage Exposure Time: 24±2h at room condition*. • Pretreatment Perform a heat treatment at 150+0/-10°C for 1h±5min and then let sit for 24±2h at room condition*.		
		Appearance	No defects or abnormalities.	Fix the capacitor to the supporting test substrate B (glass ep		
		Capacitance Change	Within ±20%	board) shown in "Complement of Test Method". Before this test, the test shown in the following is performed. • No.12 Adhesive Strength of Termination (apply force: 5N)		
		D.F.	0.05 max.	No.13 Substrate Bending Test		
		I.R.	3000MΩ or more	Next, Impulse Voltage test is performed. Each individual capacitor shall be subjected to a 5kV Impulse		
16	Durability	Voltage Proof	No defects.	(the voltage value means zero to peak) for 3 times. Then the capacitors are applied to life test. $100 (\%)$ 90 90 50 30 40 Front time (T1) = 1.2 \mu s = 1.67 T Time to half-value (T2) = 50 \mu s Apply voltage as Table for 1000h at 125+2/-0°C, relative humidity 50% max. Applied Voltage		
				AC425V (r.m.s.), except that once each hour the voltage is increased to AC1000V (r.m.s.) for 0.1s. Exposure Time: 24±2h at room condition*. • Pretreatment Perform a heat treatment at 150+0/-10°C for 1h±5min and then let sit for 24±2h at room condition*.		

* Room Condition: Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmosphere pressure: 86 to 106kPa

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GRM

GR3

GRJ

GR4

GR7

ΩĽΩ

GQM

GA2

GA3 GB

GA3 GD

GA3 GF

Η

Ч

LLM

LLR

NFM

KRM

KR3

GMA

GMD

ACaution /Notice

GA3 Series Type GF Specifications and Test Methods (2)

Continued from the preceding page. \searrow

more than two complete layers of cheesecloth. The specimens shall be subjected to 20 discharges. The interval between successive discharges shall be 5s.	No	ltem	Specification	Test Method (Ref. Standard: JIS C 5101, IEC60384)
18Active FlammabilityThe cheesecloth shall not be on fire.C1, C2: Filter capacitor 1µF±10% C3: Capacitor 0.033µF±5% L1 to L4: Rod coa choke 1.5mH±20%, 16A R: Resistor 100 2^{\pm} % C2: $< 0.068\mu$ F C2: Tank capacitor 3µF±5% 10kV Cx $\leq 1\mu$ F U-: UR±5% UR: Rated voltage 	17	Passive Flammability		position which best promotes burning. Each specimen shall only be exposed once to the flame. Time of exposure to flame: 30s Length of flame: 12±1mm Gas burner: Length 35mm min. Inside dia: 0.5±0.1mm Outside dia: 0.9mm max. Gas: Butane gas purity 95% min. Approximately 8mm Buner Flame Tissue Paper
	18	Active Flammability	The cheesecloth shall not be on fire.	The specimens shall be subjected to 20 discharges. The interval between successive discharges shall be 5s. The UAC shall be maintained for 2min after the last discharge. $S_{1}^{I} \xrightarrow{F} L_{1}^{I} \xrightarrow{L_{2}^{I}} \xrightarrow{V_{1}^{I}} \underbrace{L_{2}^{I}} \xrightarrow{V_{1}^{I}} \underbrace{L_{2}^{I}} \underbrace{V_{1}^{I}} \underbrace{V_{1}^{I}} \underbrace{V_{2}^{I}} $

GA3 Series Type GF Specifications and Test Methods (2)

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Complement of Test Method

1. Test Substrate

GRM

GR3

GRJ

GR4

GR7

дЛЯ

GOM

GA2

GA3 GB

GD GD

GA3 GF

F

LLA

LΓ

LR

NFM

КВМ

KR3

GMA

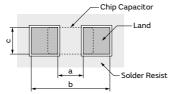
GMD

(ACaution /Notice The test substrate should be Substrate A or Substrate B as described in "Specifications and Test Methods". The specimen should be soldered by the conditions as described below. Soldering Method: Reflow soldering

Solder: Sn-3.0Ag-0.5Cu

(1) Test Substrate A

Land Dimensions

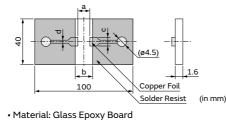


Part Number	C	imension (mm	1)
Part Number	a	b	
GA342	3.5	7.0	2.4
GA352	4.5	8.0	3.2
GA355	4.5	8.0	5.6

Material: Glass Epoxy Board

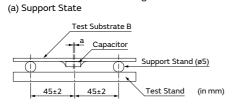
- Thickness: 1.6mm
- Thickness of Copper Foil: 0.035mm





Part Number	Dimension of Pattern (mm)					
Part Number	a	b	с	d		
GA342	3.5	7.0	2.4	1.0		
GA352	4.5	8.0	3.2	1.0		
GA355	4.5	8.0	5.6	1.0		

(b) Test State



Thickness of Copper Foil: 0.035mm

2. Test Method of Substrate Bending Test

a: ± 2 gap between support stand center and test stand

Support Stand

b: ±5 gap between support stand center and test stand center

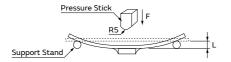
(in mm)

Pressure Stick

Material of Test Stand and Pressure Stick

The material shoud be a metal where a remarkable transformation and the distortion are not caused even if it is pressurized. • Pressurizing Speed

The pressurizing speed is pressurized at the speed of about 1mm/s until the flexure reaches a regulated value.



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